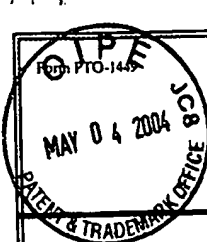


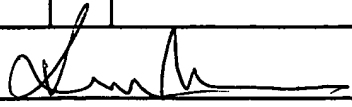
Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2493		SERIAL NO. 10/820,975	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Scott E. Moore et al.		FILING DATE April 7, 2004	
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	AA	3,446,331	8/29/1993	Boyer et al.	1	1	
	AB	4,730,922	3/15/1988	Bach et al.	1	1	
	AC						
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		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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OTHER REFERENCES (including Author, Title, Date, Portion of Page, Etc.)							
EXAMINER 				DATE CONSIDERED 04/14/2005			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2493	SERIAL NO. 10/820,575			
		LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Scott E. Moore et al.	FILING DATE March 21, 2001			
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
OJW	AA	4,152,070	5/1979	Kushner et al.				
	AB	6,100,976	8/2000	Ackerson, Bruce				
	AC	5,828,458	10/1998	Taylor et al.				
	AD	3,653,767	4/19792	Liskowitz et al.				
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	AF	6,307,630	10/2001	Banerjee et al.				
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	AH	5,912,737	6/1999	Banerjee et al.				
	AI	5,059,811	10/1991	King et al.				
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	AK	4,263,511	4/1981	Hirschberg, Joseph				
	AL	4,441,960	4/1984	Karnis et al.				
	AM	4,320,978	3/1982	Sato, Ko				
	AN	4,874,243	10/1989	Perren, Benno				
	AO	6,567,166	5/2003	Ottens et al.				
AP	5,555,583	9/1996	Berkcan, Ertugrul					
AW	5,085,831	2/1992	Hickey et al.					
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		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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	AS							
	AT							
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	AV							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-2493		PRIORITY SERIAL NO. 09/521,092	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Scott E. Moore et al.			
					PRIORITY FILING DATE March 7, 2000		PRIORITY GROUP 3723	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
<div style="border-left: 1px solid black; height: 100%; width: 10px; margin-left: 5px;"></div>	AA	5,836,805	11/1998	Obeng	1	1		
	AB	6,066,030	5/2000	Uzob	1	1		
	AC	6,077,147	6/2000	Yang et al.	1	1		
	AD	6,048,256	4/2000	Obeng et al.	1	1		
	AE	5,718,620	2/17/98	Tanaka et al.	1	1		
	AF	5,885,134	3/23/99	Shibata et al.	1	1		
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	AI	6,165,048	12/26/00	Russ et al.	1	1		
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	AL	5,923,433	7/13/1999	Giuffre et al.	1	1		
	AM	6,136,043	10/24/2000	Robinson et al.	1	1		
	AN	6,482,325 B1	11/19/2002	Corlett et al.	1	1		
	AO	6,379,538 B1	4/30/2002	Corlett et al.	1	1		
		AP	5,755,614	5/26/1998	Adams et al.	1	1	
AQ		5,664,990	9/9/1997	Adams et al.	1	1		
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						Yes	No	
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER 				DATE CONSIDERED 04/14/2005				
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Scott E. Moore et al.			
				PRIORITY FILING DATE March 7, 2000	PRIORITY GROUP 3723 <b>2877</b>		
U.S. PATENT DOCUMENTS							
* Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
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	AC						
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AH						
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	AI	"The Science and Engineering of Microelectronic Fabrication"; Campbell, Stephen A.; Oxford University Press; 1996; pp. 253-257.					
	AI	<a href="http://www.intra.com/html/sensors.htm">http://www.intra.com/html/sensors.htm</a> , Intra Technology, Sensors, 03/25/99, 2 pages					
	AJ	<a href="http://www.ftiinc.com/conference/analite/analite.htm">http://www.ftiinc.com/conference/analite/analite.htm</a> , FTI, Analite-SDI Turbidity Sensor, 03/25/99, 1 page					
	AK	<a href="http://www.customsensors.com/optimax.htm">http://www.customsensors.com/optimax.htm</a> , Custom Sensors & Technology, Inc., 6000 Series Process Photometric Analyzers, 03/25/99, 2 pages					
	AL	<a href="http://www.reflectronics.com/reflectronics_inc_contents.htm">http://www.reflectronics.com/reflectronics_inc_contents.htm</a> , Reflectronics, Inc., Fiber Optic Backscatter Sensor, 03/25/99, 1 page					
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	AT	<a href="http://www.impomag.com/O_automa/10970064.htm">http://www.impomag.com/O_automa/10970064.htm</a> , ABB Instrumentation, The Stockroom, Photodiode Sensor, 1999, 1 page					
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